

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:

Date: January 14, 2009

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/382,834

Examiner: V. P. Nguyen

Filed: August 25, 1999

Docket No.: YOR919930028US5

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND  
METHODS OF USE THEREOF

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE TO NOTICE OF FILE CORRECTED APPLICATION PAPERS**

**NOTICE OF ALLOWANCE MAILED DATED 12-11-2008**

**REMARKS**

Enclosed herewith is the corrected sheet of drawings containing Figs. 21 and 22. In the original drawings this sheet had both figures labeled as Fig. 21. On the attached corrected sheet the top Figure is Fig. 21 and the bottom figure is Fig. 22.